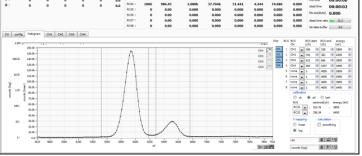
MADE IN JAPAN

High-count rate, High-sensitive by multi-element and DSP processing

SYSTEM

XSDD50 Series is all-in-one system which has detector, which is needed X-ray absorption microstructure measurement in the analysis of materials field, data acquisition board, and power supply. It was realized high-sensitivity by multiple SDD detector with high-count rate and energy resolution. Additionally, it is possible to be measured high-count rate by a transistor reset processing and DSP processing.

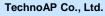
	<image/> <image/>
All element area : 455mm ² (65mm ² × 7 element)	ICR vs energy resolution
All effective area : 350mm ²	280
(collimated to 50mm ² × 7 element)	
Function : Histogram, List, Waveform, ROI-SCA	240 220 200 200 200 200 200 200
ADC : 8CH 100MSPS 14bit	80 200 180
Energy resolution : 244eV@5.9keV MnKα	
(Peakingtime 0.25ms, 1000kOCR)	
• Power supply for SDD : -200V, \pm 5V, \pm 3.3V	0 200 400 600 800 1000 1200 IOR[kcps]
Interface : Ethernet (TCP/IP)	
Accessary : Application, Instruction manual	ICR vs Energy resolution
Markade OPI and ID Paralitatic Image: A paralitatic Ima	ICR vs OCR



400k ICR 185eV@5.9keV 0.25ms Peaking Time Application

TechnoAP

Design and fabrication of electronic circuit associated with measurement control and radiation measurement



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400

600

ICR vs OCR

ICR[kcps]

800

*Please note that contents may change without prior notice.

1000

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200

Updated on 2016/08/08

1200

1400